

Supplementary Information of

Achieving Superior High-Temperature Energy Storage Performance in Polycarbonate
via Small Molecular Traps and Hydrogen Bonding

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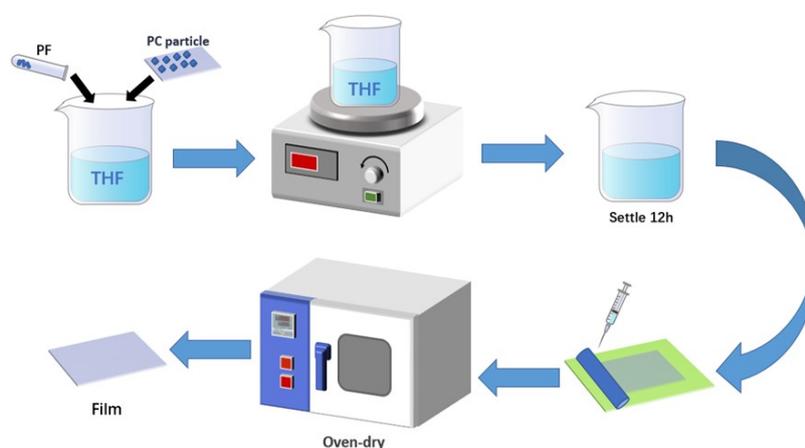


Fig.S1 Schematic illustration of the preparation process for PF/PC composite dielectric thin films

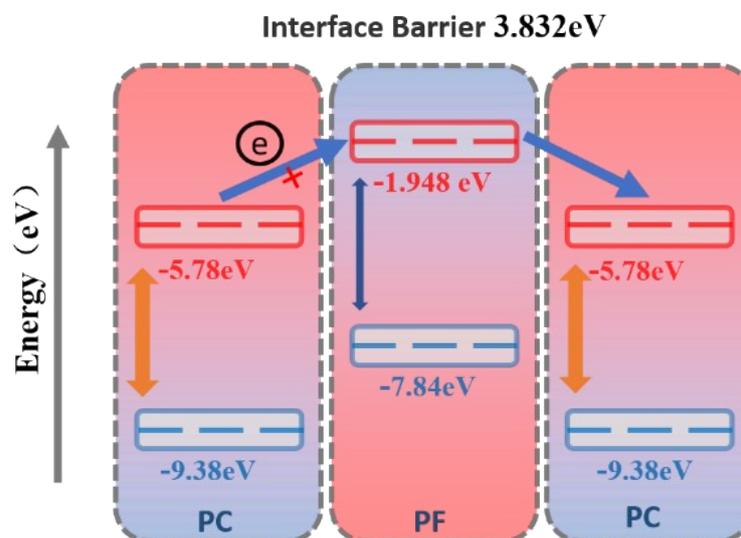


Fig.S2 Energy level alignment diagram of PF and PC

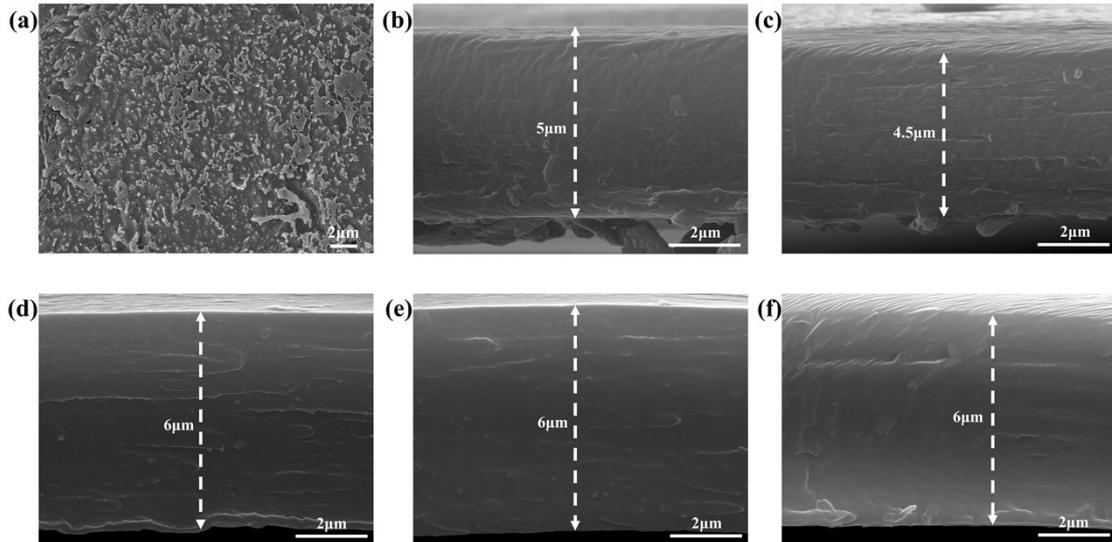


Fig.S3 (a) Morphology of PF (b) Cross-sectional image of pure PC (c) Cross-sectional image of 0.5 wt% PF/PC (d) Cross-sectional image of 1 wt% PF/PC (e) Cross-sectional image of 1.5 wt% PF/PC; (f) Cross-sectional image of 2 wt% PF/PC

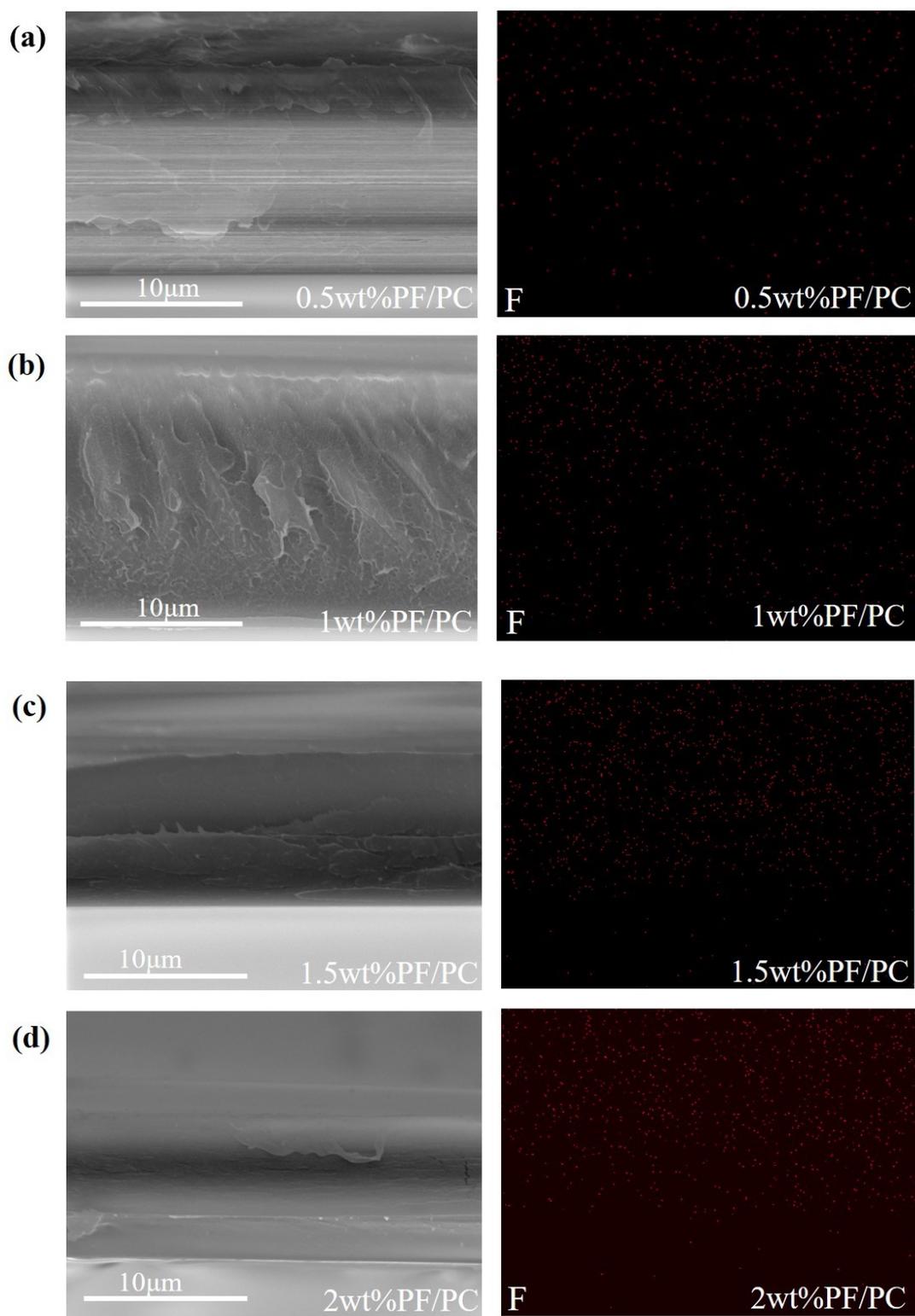


Fig.S4 (a) F element distribution in the cross-section of 0.5 wt% PF/PC (b) F element distribution in the cross-section of 1 wt% PF/PC (c) F element distribution in the cross-section of 1.5 wt% PF/PC (d) F element distribution in the cross-section of 2 wt% PF/PC

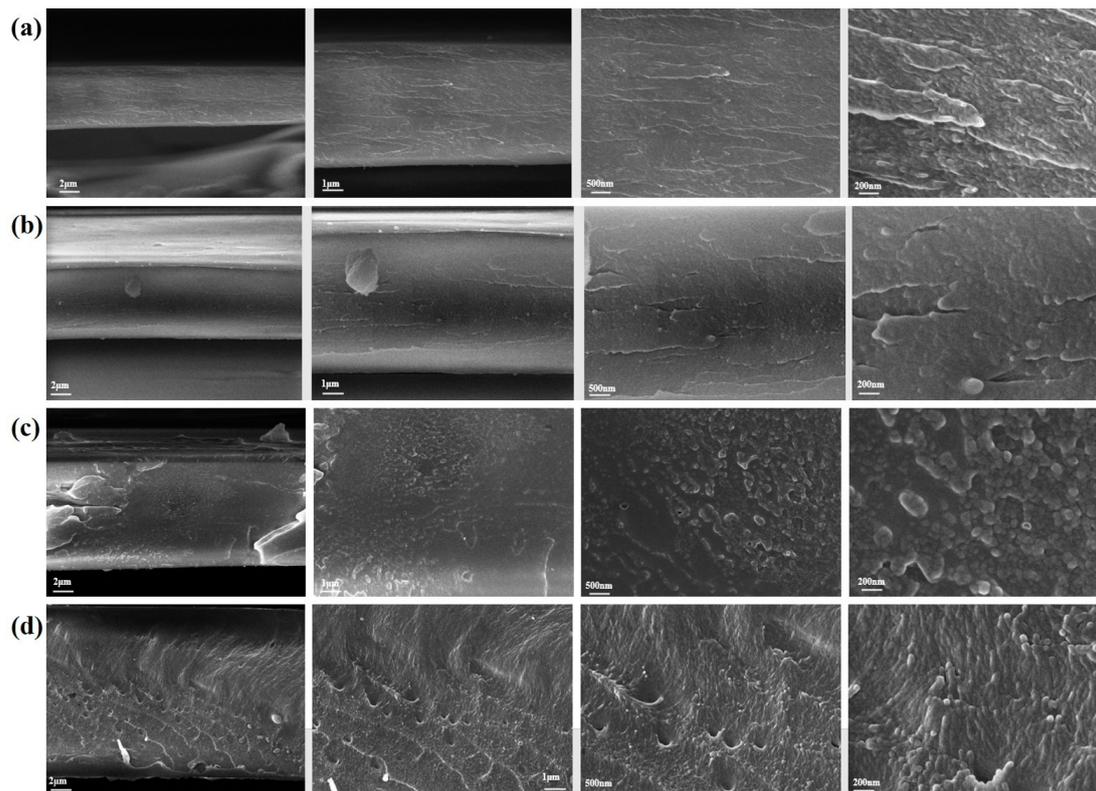


Fig.S5 (a) Microscopic SEM image of 0.5wt% PF/PC; (b) Microscopic SEM image of 1wt% PF/PC; (c) Microscopic SEM image of 1.5wt% PF/PC; (d) Microscopic SEM image of 2wt% PF/PC

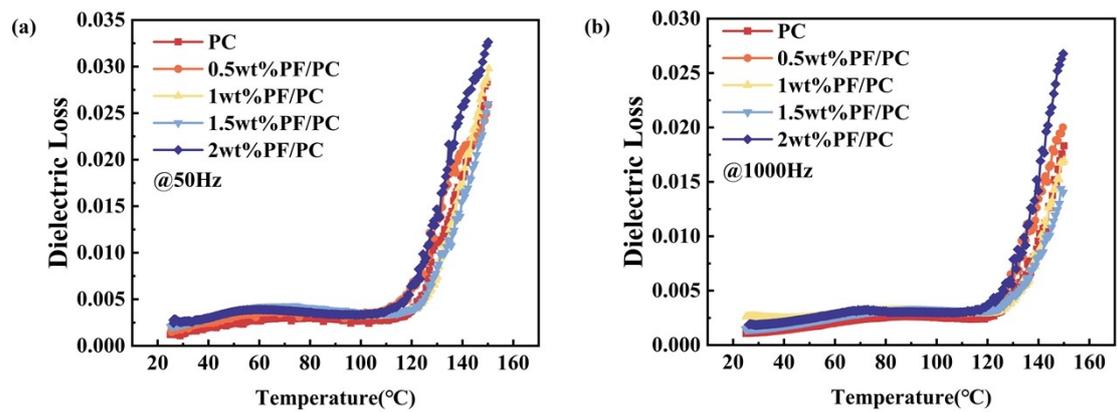


Fig.S6 (a) Dielectric loss versus temperature for PF/PC at 50 Hz. (b) Dielectric loss versus temperature for PF/PC at 1000 Hz.

The Weibull function is utilized to model the relationship between the probability of breakdown and the average breakdown field strength.

$$P(E) = 1 - \exp \left[- \left(\frac{E}{E_b} \right)^\beta \right] \#(6)$$

where $P(E)$ denotes the cumulative failure probability, E represents the breakdown field strength, E_b is the characteristic breakdown field strength (defined as the electric field at which the cumulative failure probability $P(E)$ reaches 63.2%), and β is the shape parameter.

A Fitted Model of Saltatory Conduction

$$J = n_c 2 u v e \times e^{\frac{-W_a}{K_B T}} \times \sinh \left(\frac{\lambda_e E}{2 K_B T} \right) \#(7)$$

In this equation, n_c denotes the carrier concentration, λ represents the hopping distance, ν is the attempt or escape frequency, W_a indicates the activation energy in electron volts (eV), e is the elementary charge, T denotes the temperature, and K_B is the Boltzmann constant. This expression can be simplified to yield Equation (8).

$$J = A \times \sinh (B \times E) \#(8)$$

A and B denote lumped parameters.

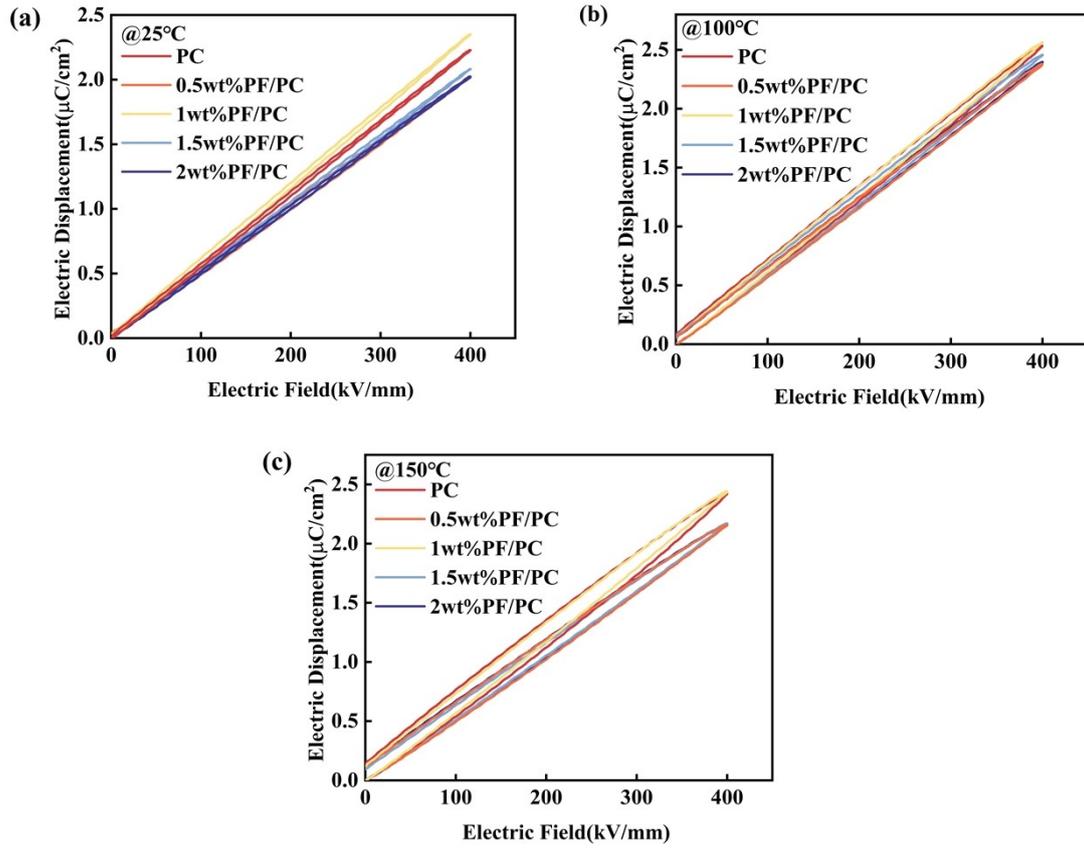


Fig.S7 (a) D - E curve at 25 °C (b) D - E curve at 100 °C (c) D - E curve at 150 °C

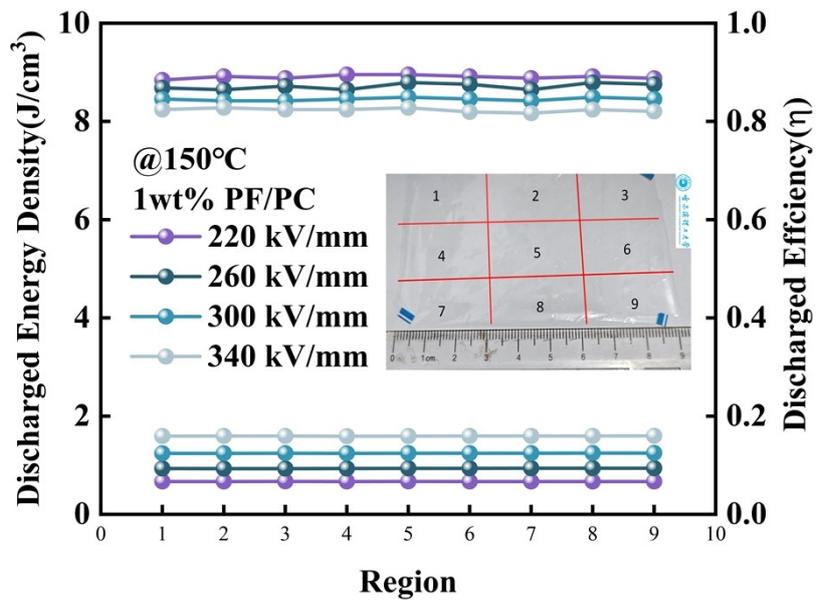


Fig. S8 Uniformity assessment of another batch of 1 wt% PF/PC composite at 150 °C

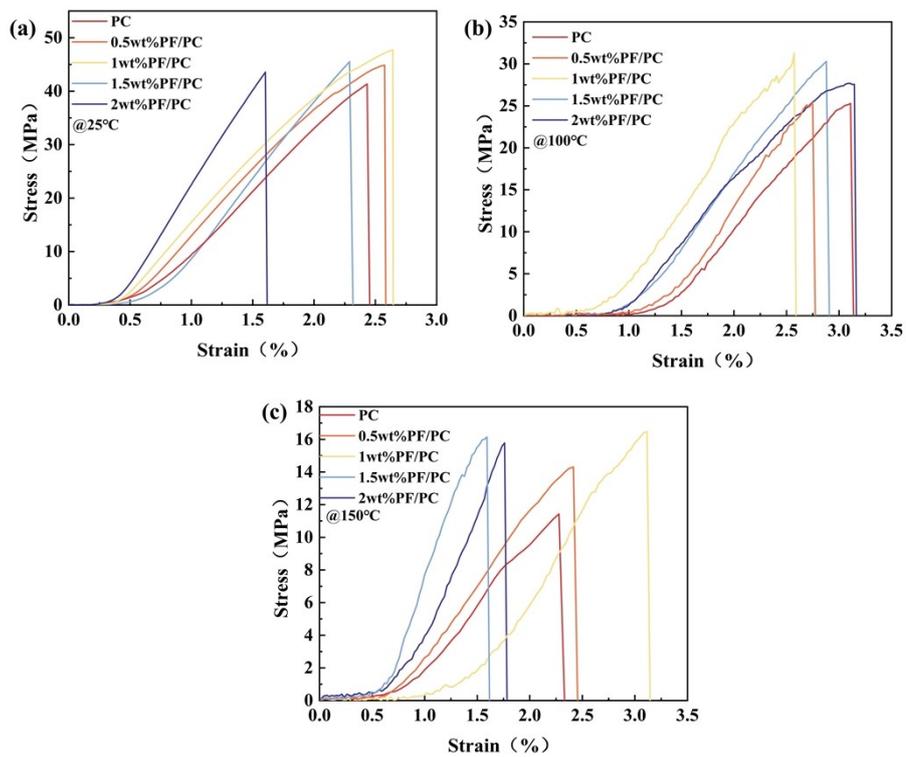


Fig.S9 (a) Stress-strain curve at 25 °C (b) Stress-strain curve at 100 °C (c) Stress-strain curve at 150 °C